

Search Notes

Application/Control No.

09/975,801

Examiner

Jung Park

Applicant(s)/Patent under
Reexamination

AGRAWAL ET AL.

Art Unit

2661

SEARCHED

Class	Subclass	Date	Examiner
370	331, 338, 349, 352, 401, 329	7/22/2005	JP
370	473	7/22/2005	JP
455	442, 436	7/22/2005	JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Chau Nguyen suggesd 370/331, 338, 401	7/22/2005	JP
Searched IEEE.	7/23/2005	JP